

X 6909

L Number	Hits	Search Text	DB	Time stamp
9	122	(scan same test with enable).ab. (scan same test with enable).ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/08/30 14:41
10	122	((scan same test with enable).ab. (scan same test with enable).ti.) and scan and test and enable	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/08/30 14:54
11	9	(scan and test and enable).ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/08/30 14:56
12	9	((scan same test with enable).ab. (scan same test with enable).ti.) and scan and test and enable) and ((scan and test and enable).ti.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/08/30 14:58
13	2	5896396.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/08/30 15:00
14	2	5831993.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/08/30 15:01
-	439	scan with test with enable	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/08/30 14:34
-	88	(scan with test with enable) and (test (test adj mode)) adj enable	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/03/12 14:49
-	89	(test (test adj mode)) adj enable adj (circuit switch circuits switches)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/03/12 15:22
-	37	((bypass) adj (circuit switch circuits switches)) and scan near (test testing)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/03/12 15:08

-	126	((test (test adj mode)) adj enable adj (circuit switch circuits switches)) (((bypass) adj (circuit switch circuits switches)) and scan near (test testing))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/03/12 15:24
-	210	((scan with test with enable) and (test (test adj mode)) adj enable) ((test (test adj mode)) adj enable adj (circuit switch circuits switches)) (((bypass) adj (circuit switch circuits switches)) and scan near (test testing))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/03/12 15:19
-	102	(test (test adj mode)) adj enable adj (circuit switch circuits switches circuitry)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/03/12 15:23
-	223	((scan with test with enable) and (test (test adj mode)) adj enable) ((test (test adj mode)) adj enable adj (circuit switch circuits switches circuitry)) (((bypass) adj (circuit switch circuits switches)) and scan near (test testing))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/03/12 15:31
-	139	((test (test adj mode)) adj enable adj (circuit switch circuits switches circuitry)) (((bypass) adj (circuit switch circuits switches)) and scan near (test testing))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/03/12 15:26
-	13	(((test (test adj mode)) adj enable adj (circuit switch circuits switches circuitry)) (((bypass) adj (circuit switch circuits switches)) and scan near (test testing))) not (((test (test adj mode)) adj enable adj (circuit switch circuits switches)) (((bypass) adj (circuit switch circuits switches)) and scan near (test testing)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/03/12 15:30
-	3	5596537.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/03/12 15:30
-	224	((scan with test with enable) and (test (test adj mode)) adj enable) ((test (test adj mode)) adj enable adj (circuit switch circuits switches circuitry)) (((bypass) adj (circuit switch circuits switches)) and scan near (test testing)) 5596537.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/03/13 13:03
-	14	"5596537"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/03/13 08:42

-	6	("4654849" "4860259").pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/03/13 12:48
-	0	scan with (test near enable near (circuit circuitry)) and nand and (MUX multiplexer multilexers multiplexes multiplexed multiplexing multiplexor)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/03/13 12:51
-	9	scan with (test near enable near (circuit circuitry))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/03/13 12:53
-	138	(test near enable near (circuit circuitry))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/03/13 12:53
-	224	((scan with test with enable) and (test (test adj mode)) adj enable) ((test (test adj mode)) adj enable adj (circuit switch circuits switches circuitry)) (((bypass) adj (circuit switch circuits switches)) and scan near (test testing)) 5596537.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/03/13 13:04